

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/665,582	HORTON, JOHN J.	
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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6392990 B1	05-2002	Tosey et al.	370/218
B	US-6574197 B1	06-2003	Kanamaru et al.	370/252
C	US-5835721	11-1998	Donahue et al.	709/224
D	US-5959974	09-1999	Badt et al.	370/233
E	US-6205579 B1	03-2001	Southgate	717/11
F	US-6622179 B2	09-2003	Welder	710/15
G	US-6747957 B1	06-2004	Pithawala et al.	709/224
H	US-6654914 B1	11-2003	Kaffine et al.	714/43
I	US-6640239 B1	10-2003	Gidwani	709/203
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6611868B1	08-2003	Arutyunov	709/200
	B	US-6470395B1	10-2002	Van Aken et al.	709/245
	C	US-6606659B1	08-2003	Hegli et al.	709/225
	D	US-6557038B1	04-2003	Becker et al.	709/227
	E	US-6609154B1	08-2003	Fuh et al.	709/225
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
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D	US-5959974	09-1999	Badt et al.	370/233
E	US-6205579 B1	03-2001	Southgate	717/11
F	US-6622179 B2	09-2003	Welder	710/15
G	US-6668282 B1	12-2003	Booth, III et al.	709/224
H	US-6654914 B1	11-2003	Kaffine et al.	714/43
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